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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	768
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	111
Number of Gates	12000
Voltage - Supply	3V ~ 3.6V, 4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	144-LBGA
Supplier Device Package	144-FPBGA (13x13)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a54sx08-fg144i

The R-cell contains a flip-flop featuring asynchronous clear, asynchronous preset, and clock enable (using the S0 and S1 lines) control signals (Figure 1-2). The R-cell registers feature programmable clock polarity selectable on a register-by-register basis. This provides additional

flexibility while allowing mapping of synthesized functions into the SX FPGA. The clock source for the R-cell can be chosen from either the hardwired clock or the routed clock.

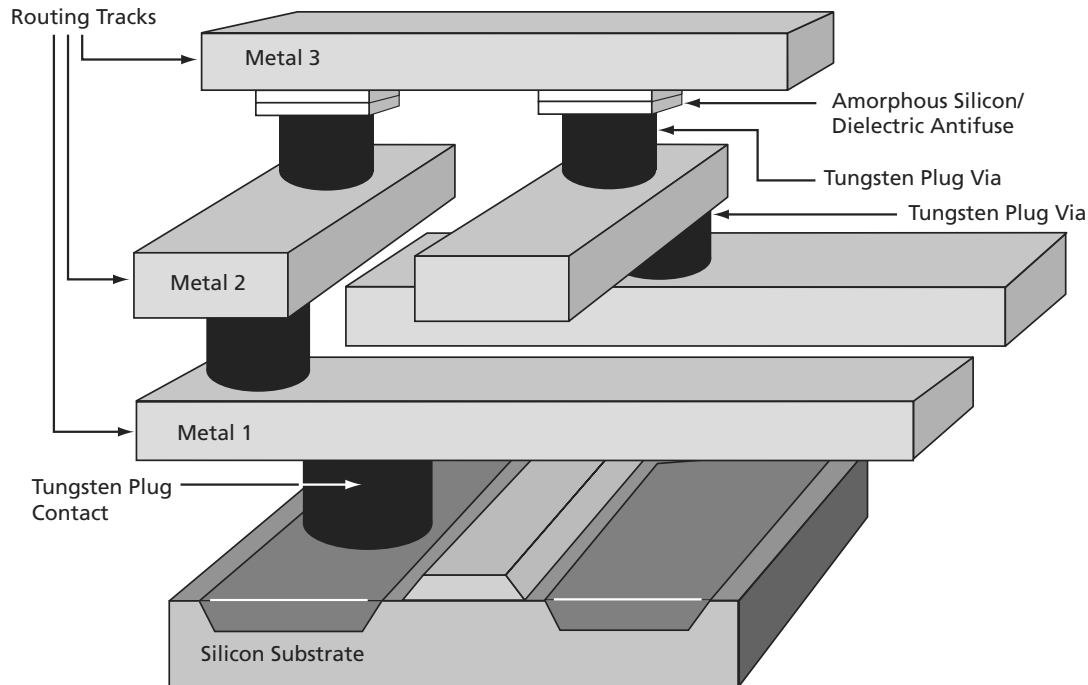


Figure 1-1 • SX Family Interconnect Elements

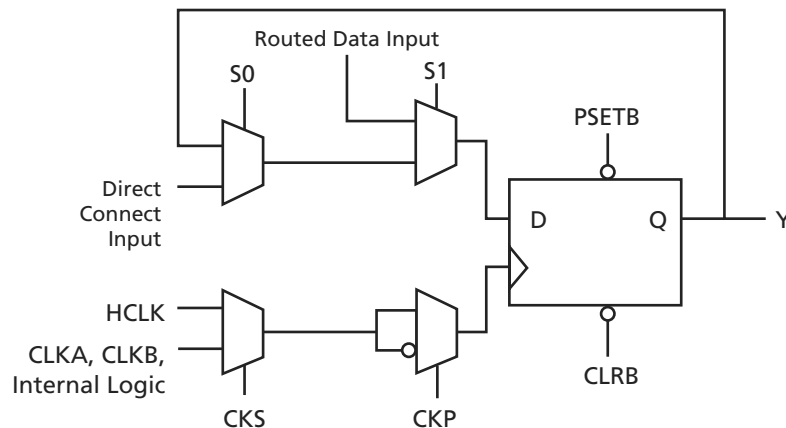


Figure 1-2 • R-Cell

The C-cell implements a range of combinatorial functions up to 5-inputs (Figure 1-3 on page 1-3). Inclusion of the DB input and its associated inverter function dramatically increases the number of combinatorial functions that can be implemented in a single module from 800 options in previous architectures to more than 4,000 in the SX architecture. An example of the improved flexibility

enabled by the inversion capability is the ability to integrate a 3-input exclusive-OR function into a single C-cell. This facilitates construction of 9-bit parity-tree functions with 2 ns propagation delays. At the same time, the C-cell structure is extremely synthesis friendly, simplifying the overall design and reducing synthesis time.

Routing Resources

Clusters and SuperClusters can be connected through the use of two innovative local routing resources called *FastConnect* and *DirectConnect*, which enable extremely fast and predictable interconnection of modules within clusters and SuperClusters (Figure 1-5 and Figure 1-6). This routing architecture also dramatically reduces the number of antifuses required to complete a circuit, ensuring the highest possible performance.

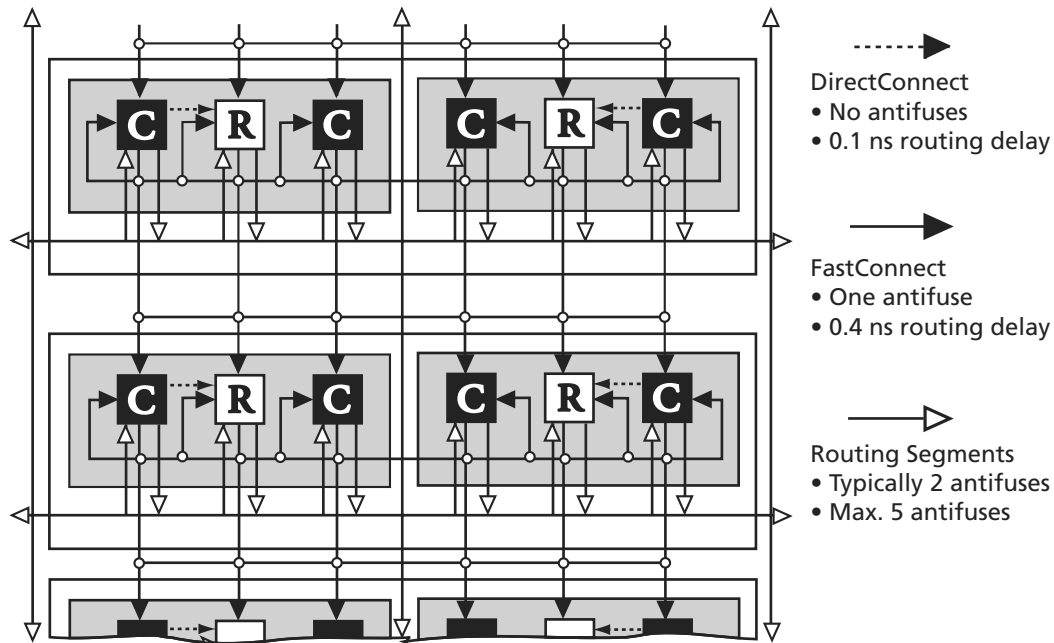


Figure 1-5 • DirectConnect and FastConnect for Type 1 SuperClusters

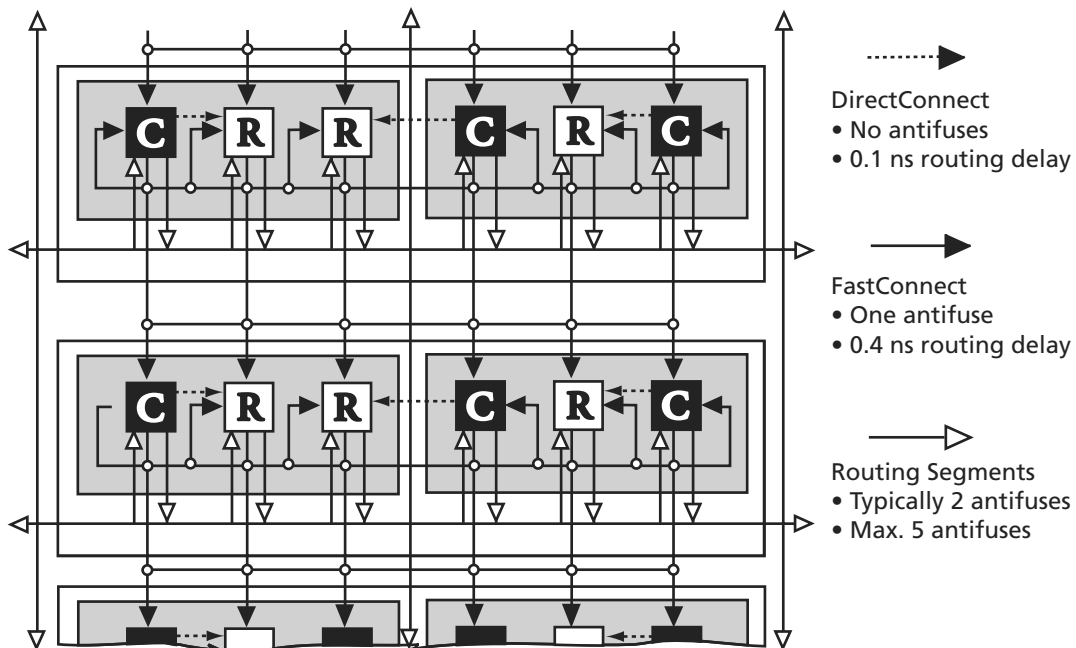


Figure 1-6 • DirectConnect and FastConnect for Type 2 SuperClusters

Boundary Scan Testing (BST)

All SX devices are IEEE 1149.1 compliant. SX devices offer superior diagnostic and testing capabilities by providing Boundary Scan Testing (BST) and probing capabilities. These functions are controlled through the special test pins in conjunction with the program fuse. The functionality of each pin is described in Table 1-2. In the dedicated test mode, TCK, TDI, and TDO are dedicated pins and cannot be used as regular I/Os. In flexible mode, TMS should be set HIGH through a pull-up resistor of 10 kΩ. TMS can be pulled LOW to initiate the test sequence.

The program fuse determines whether the device is in dedicated or flexible mode. The default (fuse not blown) is flexible mode.

Table 1-2 • Boundary Scan Pin Functionality

Program Fuse Blown (Dedicated Test Mode)	Program Fuse Not Blown (Flexible Mode)
TCK, TDI, TDO are dedicated BST pins.	TCK, TDI, TDO are flexible and may be used as I/Os.
No need for pull-up resistor for TMS	Use a pull-up resistor of 10 kΩ on TMS.

Dedicated Test Mode

In Dedicated mode, all JTAG pins are reserved for BST; designers cannot use them as regular I/Os. An internal pull-up resistor is automatically enabled on both TMS and TDI pins, and the TMS pin will function as defined in the IEEE 1149.1 (JTAG) specification.

To select Dedicated mode, users need to reserve the JTAG pins in Actel's Designer software by checking the "Reserve JTAG" box in "Device Selection Wizard" (Figure 1-7). JTAG pins comply with LVTTTL/TTL I/O specification regardless of whether they are used as a user I/O or a JTAG I/O. Refer to the Table 1-5 on page 1-8 for detailed specifications.

Development Tool Support

The SX family of FPGAs is fully supported by both the Actel Libero® Integrated Design Environment (IDE) and Designer FPGA Development software. Actel Libero IDE is a design management environment, seamlessly integrating design tools while guiding the user through the design flow, managing all design and log files, and passing necessary design data among tools. Libero IDE allows users to integrate both schematic and HDL synthesis into a single flow and verify the entire design in a single environment. Libero IDE includes Synplify® for Actel from Synplicity®, ViewDraw® for Actel from Mentor Graphics®, ModelSim® HDL Simulator from Mentor Graphics, WaveFormer Lite™ from SynaptiCAD™, and Designer software from Actel. Refer to the Libero IDE flow diagram (located on the Actel website) for more information.

Actel Designer software is a place-and-route tool and provides a comprehensive suite of backend support tools for FPGA development. The Designer software includes timing-driven place-and-route, and a world-class integrated static timing analyzer and constraints editor. With the Designer software, a user can select and lock package pins while only minimally impacting the results of place-and-route. Additionally, the back-annotation flow is compatible with all the major simulators, and the simulation results can be cross-probed with Silicon Explorer II, Actel integrated verification and logic analysis tool. Another tool included in the Designer software is the SmartGen core generator, which easily creates popular and commonly used logic functions for implementation into your schematic or HDL design. Actel Designer software is compatible with the most popular FPGA design entry and verification tools from companies such as Mentor Graphics, Synplicity, Synopsys®, and Cadence® Design Systems. The Designer software is available for both the Windows® and UNIX® operating systems.

Probe Circuit Control Pins

The Silicon Explorer II tool uses the boundary scan ports (TDI, TCK, TMS, and TDO) to select the desired nets for verification. The selected internal nets are assigned to the PRA/PRB pins for observation. Figure 1-8 on page 1-7 illustrates the interconnection between Silicon Explorer II and the FPGA to perform in-circuit verification.

Design Considerations

The TDI, TCK, TDO, PRA, and PRB pins should not be used as input or bidirectional ports. Because these pins are active during probing, critical signals input through these pins are not available while probing. In addition, the Security Fuse should not be programmed because doing so disables the Probe Circuitry.

Figure 1-7 • Device Selection Wizard

A54SX16P DC Specifications (3.3 V PCI Operation)

Table 1-8 • A54SX16P DC Specifications (3.3 V PCI Operation)

Symbol	Parameter	Condition	Min.	Max.	Units
V_{CCA}	Supply Voltage for Array		3.0	3.6	V
V_{CCR}	Supply Voltage required for Internal Biasing		3.0	3.6	V
V_{CCI}	Supply Voltage for I/Os		3.0	3.6	V
V_{IH}	Input High Voltage		$0.5V_{CC}$	$V_{CC} + 0.5$	V
V_{IL}	Input Low Voltage		-0.5	$0.3V_{CC}$	V
I_{IPU}	Input Pull-up Voltage ¹		$0.7V_{CC}$		V
I_{IL}	Input Leakage Current ²	$0 < V_{IN} < V_{CC}$		± 10	μA
V_{OH}	Output High Voltage	$I_{OUT} = -500 \mu A$	$0.9V_{CC}$		V
V_{OL}	Output Low Voltage	$I_{OUT} = 1500 \mu A$		$0.1V_{CC}$	V
C_{IN}	Input Pin Capacitance ³			10	pF
C_{CLK}	CLK Pin Capacitance		5	12	pF
C_{IDSEL}	IDSEL Pin Capacitance ⁴			8	pF

Notes:

1. This specification should be guaranteed by design. It is the minimum voltage to which pull-up resistors are calculated to pull a floated network. Applications sensitive to static power utilization should assure that the input buffer is conducting minimum current at this input voltage.
2. Input leakage currents include hi-Z output leakage for all bidirectional buffers with tristate outputs.
3. Absolute maximum pin capacitance for a PCI input is 10 pF (except for CLK).
4. Lower capacitance on this input-only pin allows for non-resistive coupling to AD[xx].

Step 1: Define Terms Used in Formula

	V_{CCA}	3.3
Module		
Number of logic modules switching at f_m (Used 50%)	m	264
Average logic modules switching rate f_m (MHz) (Guidelines: $f/10$)	f_m	20
Module capacitance C_{EQM} (pF)	C_{EQM}	4.0
Input Buffer		
Number of input buffers switching at f_n	n	1
Average input switching rate f_n (MHz) (Guidelines: $f/5$)	f_n	40
Input buffer capacitance C_{EQI} (pF)	C_{EQI}	3.4
Output Buffer		
Number of output buffers switching at f_p	p	1
Average output buffers switching rate f_p (MHz) (Guidelines: $f/10$)	f_p	20
Output buffers buffer capacitance C_{EQO} (pF)	C_{EQO}	4.7
Output Load capacitance C_L (pF)	C_L	35
RCLKA		
Number of Clock loads q_1	q_1	528
Capacitance of routed array clock (pF)	C_{EQCR}	1.6
Average clock rate (MHz)	f_{q1}	200
Fixed capacitance (pF)	r_1	138
RCLKB		
Number of Clock loads q_2	q_2	0
Capacitance of routed array clock (pF)	C_{EQCR}	1.6
Average clock rate (MHz)	f_{q2}	0
Fixed capacitance (pF)	r_2	138
HCLK		
Number of Clock loads	s_1	0
Variable capacitance of dedicated array clock (pF)	C_{EQHV}	0.61 5
Fixed capacitance of dedicated array clock (pF)	C_{EQHF}	96
Average clock rate (MHz)	f_{s1}	0

Step 2: Calculate Dynamic Power Consumption

$V_{CCA} \times V_{CCA}$	10.89
$m \times f_m \times C_{EQM}$	0.02112
$n \times f_n \times C_{EQI}$	0.000136
$p \times f_p \times (C_{EQO} + C_L)$	0.000794
$0.5 (q_1 \times C_{EQCR} \times f_{q1}) + (r_1 \times f_{q1})$	0.11208
$0.5 (q_2 \times C_{EQCR} \times f_{q2}) + (r_2 \times f_{q2})$	0
$0.5 (s_1 \times C_{EQHV} \times f_{s1}) + (C_{EQHF} \times f_{s1})$	0
$P_{AC} = 1.461 \text{ W}$	

Step 3: Calculate DC Power Dissipation**DC Power Dissipation**

$$P_{DC} = (I_{standby}) \times V_{CCA} + (I_{standby}) \times V_{CCR} + (I_{standby}) \times V_{CCI} + X \times V_{OL} \times I_{OL} + Y(V_{CCI} - V_{OH}) \times V_{OH}$$

EQ 1-12

For a rough estimate of DC Power Dissipation, only use $P_{DC} = (I_{standby}) \times V_{CCA}$. The rest of the formula provides a very small number that can be considered negligible.

$$P_{DC} = (I_{standby}) \times V_{CCA}$$

$$P_{DC} = .55 \text{ mA} \times 3.3 \text{ V}$$

$$P_{DC} = 0.001815 \text{ W}$$

Step 4: Calculate Total Power Consumption

$$P_{Total} = P_{AC} + P_{DC}$$

$$P_{Total} = 1.461 + 0.001815$$

$$P_{Total} = 1.4628 \text{ W}$$

Step 5: Compare Estimated Power Consumption against Characterized Power Consumption

The estimated total power consumption for this design is 1.46 W. The characterized power consumption for this design at 200 MHz is 1.0164 W.

Table 1-15 • Package Thermal Characteristics

Package Type	Pin Count	θ_{jc}	θ_{ja} Still Air	θ_{ja} 300 ft/min.	Units
Plastic Leaded Chip Carrier (PLCC)	84	12	32	22	°C/W
Thin Quad Flat Pack (TQFP)	144	11	32	24	°C/W
Thin Quad Flat Pack (TQFP)	176	11	28	21	°C/W
Very Thin Quad Flatpack (VQFP)	100	10	38	32	°C/W
Plastic Quad Flat Pack (PQFP) without Heat Spreader	208	8	30	23	°C/W
Plastic Quad Flat Pack (PQFP) with Heat Spreader	208	3.8	20	17	°C/W
Plastic Ball Grid Array (PBGA)	272	3	20	14.5	°C/W
Plastic Ball Grid Array (PBGA)	313	3	23	17	°C/W
Plastic Ball Grid Array (PBGA)	329	3	18	13.5	°C/W
Fine Pitch Ball Grid Array (FBGA)	144	3.8	38.8	26.7	°C/W

Note: SX08 does not have a heat spreader.

Table 1-16 • Temperature and Voltage Derating Factors*

V_{CCA}	Junction Temperature						
	-55	-40	0	25	70	85	125
3.0	0.75	0.78	0.87	0.89	1.00	1.04	1.16
3.3	0.70	0.73	0.82	0.83	0.93	0.97	1.08
3.6	0.66	0.69	0.77	0.78	0.87	0.92	1.02

Note: *Normalized to worst-case commercial, $T_J = 70^\circ\text{C}$, $V_{CCA} = 3.0\text{ V}$

The diagram illustrates the timing of a digital circuit, categorized into three main delay regions: Input Delays, Internal Delays, and Output Delays.

Input Delays: The input signal enters through an I/O Module with a delay $t_{INY} = 1.5 \text{ ns}$. The signal then reaches a Combinatorial Cell with a delay $t_{PD} = 0.6 \text{ ns}$. The signal also branches to two Register Cells. The first Register Cell has a setup delay $t_{SUD} = 0.5 \text{ ns}$ and a hold delay $t_{HD} = 0.0 \text{ ns}$. The second Register Cell has a setup delay $t_{SUD} = 0.5 \text{ ns}$ and a hold delay $t_{HD} = 0.0 \text{ ns}$. The signal also branches to an output I/O Module with a delay $t_{DHL} = 1.6 \text{ ns}$.

Internal Delays: The signal enters the Combinatorial Cell with a delay $t_{PD} = 0.6 \text{ ns}$. The signal also branches to two Register Cells. The first Register Cell has a delay $t_{RD1} = 0.3 \text{ ns}$ and a reset delay $t_{RCO} = 0.8 \text{ ns}$. The second Register Cell has a delay $t_{RD1} = 0.3 \text{ ns}$ and a reset delay $t_{RCO} = 0.8 \text{ ns}$.

Output Delays: The signal enters the output I/O Module with a delay $t_{DHL} = 1.6 \text{ ns}$. The signal also branches to two Register Cells. The first Register Cell has a delay $t_{RD1} = 0.3 \text{ ns}$ and a reset delay $t_{RCO} = 0.8 \text{ ns}$. The second Register Cell has a delay $t_{RD1} = 0.3 \text{ ns}$ and a reset delay $t_{RCO} = 0.8 \text{ ns}$. The signal also branches to an output I/O Module with a delay $t_{DHL} = 1.6 \text{ ns}$ and a delay $t_{ENZH} = 2.3 \text{ ns}$.

Timing Parameters:

- $t_{INY} = 1.5 \text{ ns}$ (Input delay)
- $t_{PD} = 0.6 \text{ ns}$ (Combinatorial delay)
- $t_{RD1} = 0.3 \text{ ns}$ (Register delay)
- $t_{RCO} = 0.8 \text{ ns}$ (Reset delay)
- $t_{SUD} = 0.5 \text{ ns}$ (Setup delay)
- $t_{HD} = 0.0 \text{ ns}$ (Hold delay)
- $t_{DHL} = 1.6 \text{ ns}$ (Output delay)
- $t_{ENZH} = 2.3 \text{ ns}$ (Output delay)

Timing Diagram: The diagram shows the signal transitions and the timing of the clock signals. The clock signals are labeled "Routed Clock" and "Hardwired Clock". The "Routed Clock" has a delay $t_{RCKH} = 1.5 \text{ ns}$ (100% Load) and a frequency $F_{MAX} = 250 \text{ MHz}$. The "Hardwired Clock" has a delay $t_{HCKH} = 1.0 \text{ ns}$ and a frequency $F_{HMAX} = 320 \text{ MHz}$.

Figure 1-12 • SX Timing Model

Routed Clock

EQ 1-15

EQ 1-17

Clock-to-Out (Pin-to-Pin)

EQ 1-16

EQ 1-18

Register Cell Timing Characteristics

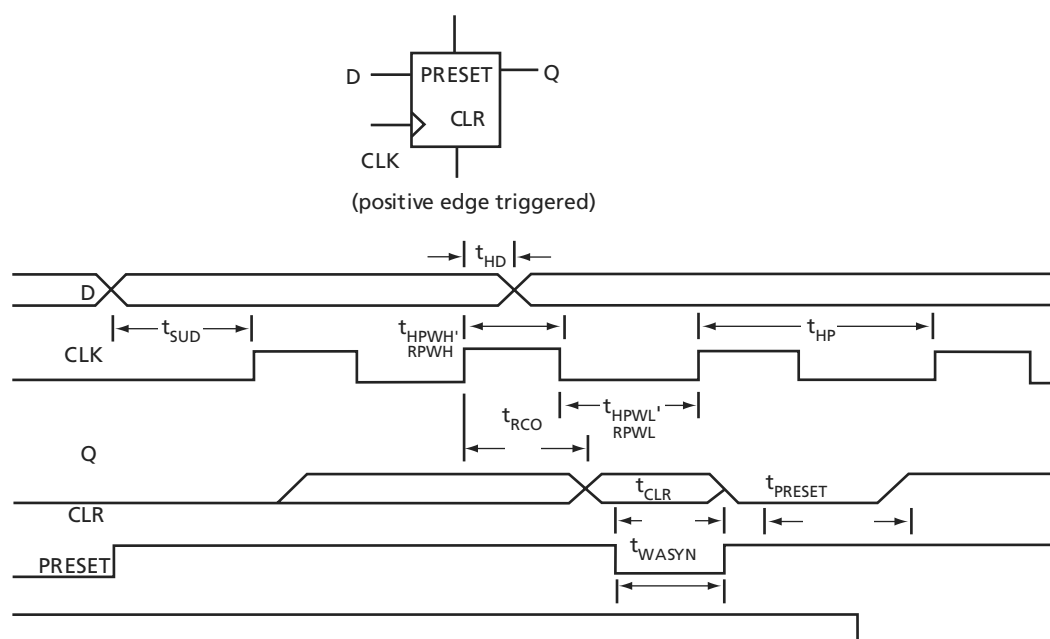


Figure 1-17 • Flip-Flops

Timing Characteristics

Timing characteristics for SX devices fall into three categories: family-dependent, device-dependent, and design-dependent. The input and output buffer characteristics are common to all SX family members. Internal routing delays are device-dependent. Design dependency means actual delays are not determined until after placement and routing of the user's design is complete. Delay values may then be determined by using the DirectTime Analyzer utility or performing simulation with post-layout delays.

Critical Nets and Typical Nets

Propagation delays are expressed only for typical nets, which are used for initial design performance evaluation. Critical net delays can then be applied to the most time-critical paths. Critical nets are determined by net property assignment prior to placement and routing. Up to 6% of the nets in a design may be designated as critical, while 90% of the nets in a design are typical.

Long Tracks

Some nets in the design use long tracks. Long tracks are special routing resources that span multiple rows, columns, or modules. Long tracks employ three and sometimes five antifuse connections. This increases capacitance and resistance, resulting in longer net delays for macros connected to long tracks. Typically up to 6 percent of nets in a fully utilized device require long tracks. Long tracks contribute approximately 4 ns to 8.4 ns delay. This additional delay is represented statistically in higher fanout ($FO = 24$) routing delays in the datasheet specifications section.

Timing Derating

SX devices are manufactured in a CMOS process. Therefore, device performance varies according to temperature, voltage, and process variations. Minimum timing parameters reflect maximum operating voltage, minimum operating temperature, and best-case processing. Maximum timing parameters reflect minimum operating voltage, maximum operating temperature, and worst-case processing.

A54SX16 Timing Characteristics

Table 1-18 • **A54SX16 Timing Characteristics**
(Worst-Case Commercial Conditions, $V_{CCR} = 4.75\text{ V}$, $V_{CCA}, V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
C-Cell Propagation Delays ¹										
t _{PD}	Internal Array Module	0.6		0.7		0.8		0.9		ns
Predicted Routing Delays ²										
t _{DC}	FO = 1 Routing Delay, Direct Connect	0.1		0.1		0.1		0.1		ns
t _{FC}	FO = 1 Routing Delay, Fast Connect	0.3		0.4		0.4		0.5		ns
t _{RD1}	FO = 1 Routing Delay	0.3		0.4		0.4		0.5		ns
t _{RD2}	FO = 2 Routing Delay	0.6		0.7		0.8		0.9		ns
t _{RD3}	FO = 3 Routing Delay	0.8		0.9		1.0		1.2		ns
t _{RD4}	FO = 4 Routing Delay	1.0		1.2		1.4		1.6		ns
t _{RD8}	FO = 8 Routing Delay	1.9		2.2		2.5		2.9		ns
t _{RD12}	FO = 12 Routing Delay	2.8		3.2		3.7		4.3		ns
R-Cell Timing										
t _{RCO}	Sequential Clock-to-Q	0.8		1.1		1.2		1.4		ns
t _{CLR}	Asynchronous Clear-to-Q	0.5		0.6		0.7		0.8		ns
t _{PRESET}	Asynchronous Preset-to-Q	0.7		0.8		0.9		1.0		ns
t _{SUD}	Flip-Flop Data Input Set-Up	0.5		0.5		0.7		0.8		ns
t _{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		ns
t _{WASYN}	Asynchronous Pulse Width	1.4		1.6		1.8		2.1		ns
Input Module Propagation Delays										
t _{INYH}	Input Data Pad-to-Y HIGH	1.5		1.7		1.9		2.2		ns
t _{INYL}	Input Data Pad-to-Y LOW	1.5		1.7		1.9		2.2		ns
Predicted Input Routing Delays ²										
t _{IRD1}	FO = 1 Routing Delay	0.3		0.4		0.4		0.5		ns
t _{IRD2}	FO = 2 Routing Delay	0.6		0.7		0.8		0.9		ns
t _{IRD3}	FO = 3 Routing Delay	0.8		0.9		1.0		1.2		ns
t _{IRD4}	FO = 4 Routing Delay	1.0		1.2		1.4		1.6		ns
t _{IRD8}	FO = 8 Routing Delay	1.9		2.2		2.5		2.9		ns
t _{IRD12}	FO = 12 Routing Delay	2.8		3.2		3.7		4.3		ns

Notes:

1. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.
3. Delays based on 35 pF loading, except t_{ENZL} and t_{ENZH} . For t_{ENZL} and t_{ENZH} , the loading is 5 pF.

A54SX16P Timing Characteristics

Table 1-19 • **A54SX16P Timing Characteristics**
(Worst-Case Commercial Conditions, $V_{CCR} = 4.75\text{ V}$, $V_{CCA}, V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
C-Cell Propagation Delays ¹										
t _{PD}	Internal Array Module	0.6		0.7		0.8		0.9		ns
Predicted Routing Delays ²										
t _{DC}	FO = 1 Routing Delay, Direct Connect	0.1		0.1		0.1		0.1		ns
t _{FC}	FO = 1 Routing Delay, Fast Connect	0.3		0.4		0.4		0.5		ns
t _{RD1}	FO = 1 Routing Delay	0.3		0.4		0.4		0.5		ns
t _{RD2}	FO = 2 Routing Delay	0.6		0.7		0.8		0.9		ns
t _{RD3}	FO = 3 Routing Delay	0.8		0.9		1.0		1.2		ns
t _{RD4}	FO = 4 Routing Delay	1.0		1.2		1.4		1.6		ns
t _{RD8}	FO = 8 Routing Delay	1.9		2.2		2.5		2.9		ns
t _{RD12}	FO = 12 Routing Delay	2.8		3.2		3.7		4.3		ns
R-Cell Timing										
t _{RCO}	Sequential Clock-to-Q	0.9		1.1		1.3		1.4		ns
t _{CLR}	Asynchronous Clear-to-Q	0.5		0.6		0.7		0.8		ns
t _{PRESET}	Asynchronous Preset-to-Q	0.7		0.8		0.9		1.0		ns
t _{SUD}	Flip-Flop Data Input Set-Up	0.5		0.5		0.7		0.8		ns
t _{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		ns
t _{WASYN}	Asynchronous Pulse Width	1.4		1.6		1.8		2.1		ns
Input Module Propagation Delays										
t _{INYH}	Input Data Pad-to-Y HIGH	1.5		1.7		1.9		2.2		ns
t _{INYL}	Input Data Pad-to-Y LOW	1.5		1.7		1.9		2.2		ns
Predicted Input Routing Delays ²										
t _{IRD1}	FO = 1 Routing Delay	0.3		0.4		0.4		0.5		ns
t _{IRD2}	FO = 2 Routing Delay	0.6		0.7		0.8		0.9		ns
t _{IRD3}	FO = 3 Routing Delay	0.8		0.9		1.0		1.2		ns
t _{IRD4}	FO = 4 Routing Delay	1.0		1.2		1.4		1.6		ns
t _{IRD8}	FO = 8 Routing Delay	1.9		2.2		2.5		2.9		ns
t _{IRD12}	FO = 12 Routing Delay	2.8		3.2		3.7		4.3		ns

Note:

1. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.
3. Delays based on 10 pF loading.

A54SX32 Timing Characteristics

Table 1-20 • A54SX32 Timing Characteristics
(Worst-Case Commercial Conditions, $V_{CCR} = 4.75\text{ V}$, $V_{CCA}, V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
C-Cell Propagation Delays ¹										
t _{PD}	Internal Array Module	0.6		0.7		0.8		0.9		ns
Predicted Routing Delays ²										
t _{DC}	FO = 1 Routing Delay, Direct Connect	0.1		0.1		0.1		0.1		ns
t _{FC}	FO = 1 Routing Delay, Fast Connect	0.3		0.4		0.4		0.5		ns
t _{RD1}	FO = 1 Routing Delay	0.3		0.4		0.4		0.5		ns
t _{RD2}	FO = 2 Routing Delay	0.7		0.8		0.9		1.0		ns
t _{RD3}	FO = 3 Routing Delay	1.0		1.2		1.4		1.6		ns
t _{RD4}	FO = 4 Routing Delay	1.4		1.6		1.8		2.1		ns
t _{RD8}	FO = 8 Routing Delay	2.7		3.1		3.5		4.1		ns
t _{RD12}	FO = 12 Routing Delay	4.0		4.7		5.3		6.2		ns
R-Cell Timing										
t _{RCO}	Sequential Clock-to-Q	0.8		1.1		1.3		1.4		ns
t _{CLR}	Asynchronous Clear-to-Q	0.5		0.6		0.7		0.8		ns
t _{PRESET}	Asynchronous Preset-to-Q	0.7		0.8		0.9		1.0		ns
t _{SUD}	Flip-Flop Data Input Set-Up	0.5		0.6		0.7		0.8		ns
t _{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		ns
t _{WASYN}	Asynchronous Pulse Width	1.4		1.6		1.8		2.1		ns
Input Module Propagation Delays										
t _{INYH}	Input Data Pad-to-Y HIGH	1.5		1.7		1.9		2.2		ns
t _{INYL}	Input Data Pad-to-Y LOW	1.5		1.7		1.9		2.2		ns
Predicted Input Routing Delays ²										
t _{IRD1}	FO = 1 Routing Delay	0.3		0.4		0.4		0.5		ns
t _{IRD2}	FO = 2 Routing Delay	0.7		0.8		0.9		1.0		ns
t _{IRD3}	FO = 3 Routing Delay	1.0		1.2		1.4		1.6		ns
t _{IRD4}	FO = 4 Routing Delay	1.4		1.6		1.8		2.1		ns
t _{IRD8}	FO = 8 Routing Delay	2.7		3.1		3.5		4.1		ns
t _{IRD12}	FO = 12 Routing Delay	4.0		4.7		5.3		6.2		ns

Note:

- For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.
- Delays based on 35 pF loading, except t_{ENZL} and t_{ENZH} . For t_{ENZL} and t_{ENZH} the loading is 5 pF.

Table 1-20 • A54SX32 Timing Characteristics (Continued)
(Worst-Case Commercial Conditions, $V_{CCR} = 4.75\text{ V}$, $V_{CCA}, V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Network										
t _{HCKH}	Input LOW to HIGH (pad to R-Cell input)	1.9		2.1		2.4		2.8		ns
t _{HCKL}	Input HIGH to LOW (pad to R-Cell input)	1.9		2.1		2.4		2.8		ns
t _{HPWH}	Minimum Pulse Width HIGH	1.4		1.6		1.8		2.1		ns
t _{HPWL}	Minimum Pulse Width LOW	1.4		1.6		1.8		2.1		ns
t _{HCKSW}	Maximum Skew	0.3		0.4		0.4		0.5		ns
t _{HP}	Minimum Period	2.7		3.1		3.6		4.2		ns
f _{HMAX}	Maximum Frequency	350		320		280		240		MHz
Routed Array Clock Networks										
t _{RCKH}	Input LOW to HIGH (light load) (pad to R-Cell input)	2.4		2.7		3.0		3.5		ns
t _{RCKL}	Input HIGH to LOW (light load) (pad to R-Cell input)	2.4		2.7		3.1		3.6		ns
t _{RCKH}	Input LOW to HIGH (50% load) (pad to R-Cell input)	2.7		3.0		3.5		4.1		ns
t _{RCKL}	Input HIGH to LOW (50% load) (pad to R-Cell input)	2.7		3.1		3.6		4.2		ns
t _{RCKH}	Input LOW to HIGH (100% load) (pad to R-Cell input)	2.7		3.1		3.5		4.1		ns
t _{RCKL}	Input HIGH to LOW (100% load) (pad to R-Cell input)	2.8		3.2		3.6		4.3		ns
t _{RPWH}	Min. Pulse Width HIGH	2.1		2.4		2.7		3.2		ns
t _{RPWL}	Min. Pulse Width LOW	2.1		2.4		2.7		3.2		ns
t _{RCKSW}	Maximum Skew (light load)	0.85		0.98		1.1		1.3		ns
t _{RCKSW}	Maximum Skew (50% load)	1.23		1.4		1.6		1.9		ns
t _{RCKSW}	Maximum Skew (100% load)	1.30		1.5		1.7		2.0		ns
TTL Output Module Timing ³										
t _{DLH}	Data-to-Pad LOW to HIGH	1.6		1.9		2.1		2.5		ns
t _{DHL}	Data-to-Pad HIGH to LOW	1.6		1.9		2.1		2.5		ns
t _{ENZL}	Enable-to-Pad, Z to L	2.1		2.4		2.8		3.2		ns
t _{ENZH}	Enable-to-Pad, Z to H	2.3		2.7		3.1		3.6		ns
t _{ENLZ}	Enable-to-Pad, L to Z	1.4		1.7		1.9		2.2		ns
t _{ENHZ}	Enable-to-Pad, H to Z	1.3		1.5		1.7		2.0		ns

Note:

- For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.
- Delays based on 35 pF loading, except t_{ENZL} and t_{ENZH} . For t_{ENZL} and t_{ENZH} the loading is 5 pF.

Package Pin Assignments

84-Pin PLCC

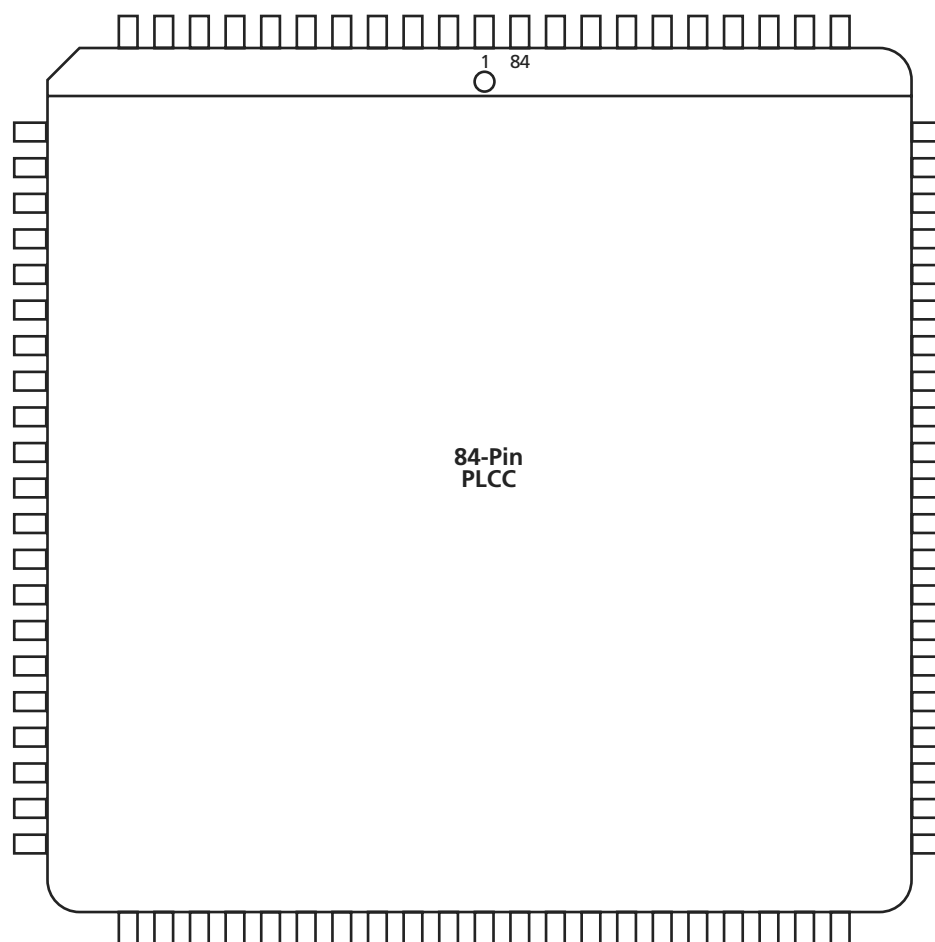


Figure 2-1 • 84-Pin PLCC (Top View)

Note

For Package Manufacturing and Environmental information, visit the Package Resource center at <http://www.actel.com/products/rescenter/package/index.html>.

84-Pin PLCC	
Pin Number	A54SX08 Function
1	V _{CCR}
2	GND
3	V _{CCA}
4	PRA, I/O
5	I/O
6	I/O
7	V _{CCI}
8	I/O
9	I/O
10	I/O
11	TCK, I/O
12	TDI, I/O
13	I/O
14	I/O
15	I/O
16	TMS
17	I/O
18	I/O
19	I/O
20	I/O
21	I/O
22	I/O
23	I/O
24	I/O
25	I/O
26	I/O
27	GND
28	V _{CCI}
29	I/O
30	I/O
31	I/O
32	I/O
33	I/O
34	I/O
35	I/O

84-Pin PLCC	
Pin Number	A54SX08 Function
36	I/O
37	I/O
38	I/O
39	I/O
40	PRB, I/O
41	V _{CCA}
42	GND
43	V _{CCR}
44	I/O
45	HCLK
46	I/O
47	I/O
48	I/O
49	I/O
50	I/O
51	I/O
52	TDO, I/O
53	I/O
54	I/O
55	I/O
56	I/O
57	I/O
58	I/O
59	V _{CCA}
60	V _{CCI}
61	GND
62	I/O
63	I/O
64	I/O
65	I/O
66	I/O
67	I/O
68	V _{CCA}
69	GND
70	I/O

84-Pin PLCC	
Pin Number	A54SX08 Function
71	I/O
72	I/O
73	I/O
74	I/O
75	I/O
76	I/O
77	I/O
78	I/O
79	I/O
80	I/O
81	I/O
82	I/O
83	CLKA
84	CLKB

208-Pin PQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
1	GND	GND	GND
2	TDI, I/O	TDI, I/O	TDI, I/O
3	I/O	I/O	I/O
4	NC	I/O	I/O
5	I/O	I/O	I/O
6	NC	I/O	I/O
7	I/O	I/O	I/O
8	I/O	I/O	I/O
9	I/O	I/O	I/O
10	I/O	I/O	I/O
11	TMS	TMS	TMS
12	V _{CCI}	V _{CCI}	V _{CCI}
13	I/O	I/O	I/O
14	NC	I/O	I/O
15	I/O	I/O	I/O
16	I/O	I/O	I/O
17	NC	I/O	I/O
18	I/O	I/O	I/O
19	I/O	I/O	I/O
20	NC	I/O	I/O
21	I/O	I/O	I/O
22	I/O	I/O	I/O
23	NC	I/O	I/O
24	I/O	I/O	I/O
25	V _{CCR}	V _{CCR}	V _{CCR}
26	GND	GND	GND
27	V _{CCA}	V _{CCA}	V _{CCA}
28	GND	GND	GND
29	I/O	I/O	I/O
30	I/O	I/O	I/O
31	NC	I/O	I/O
32	I/O	I/O	I/O
33	I/O	I/O	I/O
34	I/O	I/O	I/O
35	NC	I/O	I/O
36	I/O	I/O	I/O

208-Pin PQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
37	I/O	I/O	I/O
38	I/O	I/O	I/O
39	NC	I/O	I/O
40	V _{CCI}	V _{CCI}	V _{CCI}
41	V _{CCA}	V _{CCA}	V _{CCA}
42	I/O	I/O	I/O
43	I/O	I/O	I/O
44	I/O	I/O	I/O
45	I/O	I/O	I/O
46	I/O	I/O	I/O
47	I/O	I/O	I/O
48	NC	I/O	I/O
49	I/O	I/O	I/O
50	NC	I/O	I/O
51	I/O	I/O	I/O
52	GND	GND	GND
53	I/O	I/O	I/O
54	I/O	I/O	I/O
55	I/O	I/O	I/O
56	I/O	I/O	I/O
57	I/O	I/O	I/O
58	I/O	I/O	I/O
59	I/O	I/O	I/O
60	V _{CCI}	V _{CCI}	V _{CCI}
61	NC	I/O	I/O
62	I/O	I/O	I/O
63	I/O	I/O	I/O
64	NC	I/O	I/O
65*	I/O	I/O	NC*
66	I/O	I/O	I/O
67	NC	I/O	I/O
68	I/O	I/O	I/O
69	I/O	I/O	I/O
70	NC	I/O	I/O
71	I/O	I/O	I/O
72	I/O	I/O	I/O

Note: * Note that Pin 65 in the A54SX32—PQ208 is a no connect (NC).

100-Pin VQFP

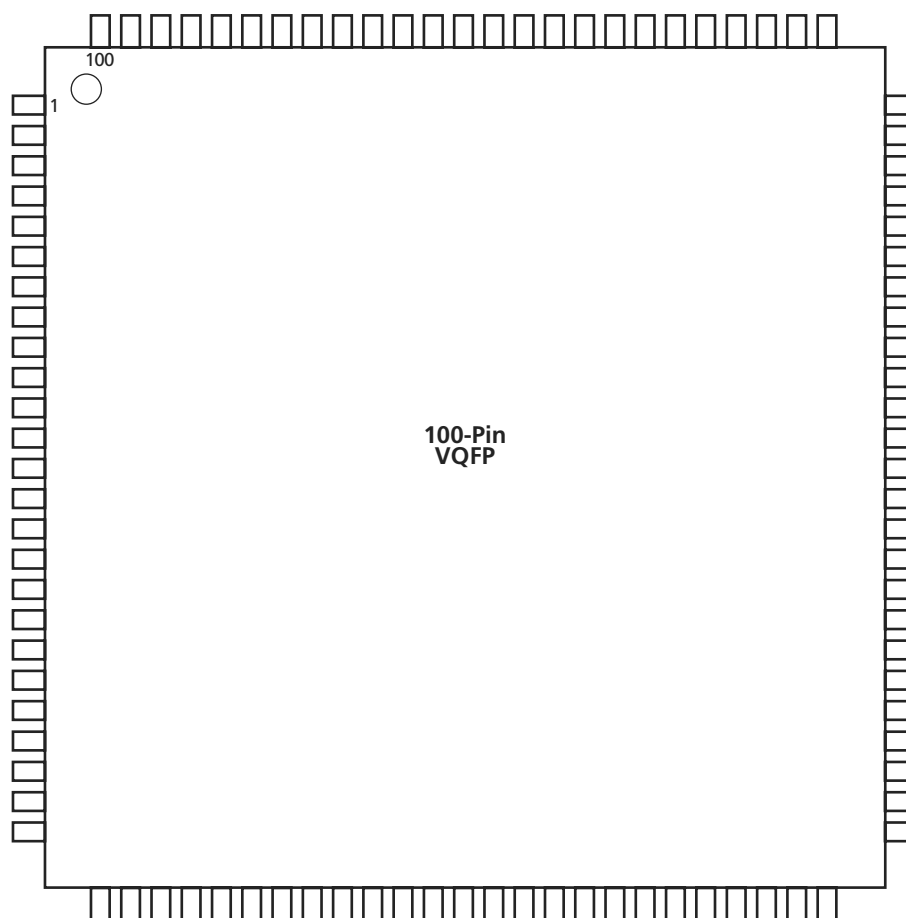


Figure 2-5 • 100-Pin VQFP (Top View)

Note

For Package Manufacturing and Environmental information, visit the Package Resource center at <http://www.actel.com/products/rescenter/package/index.html>.

313-Pin PBGA

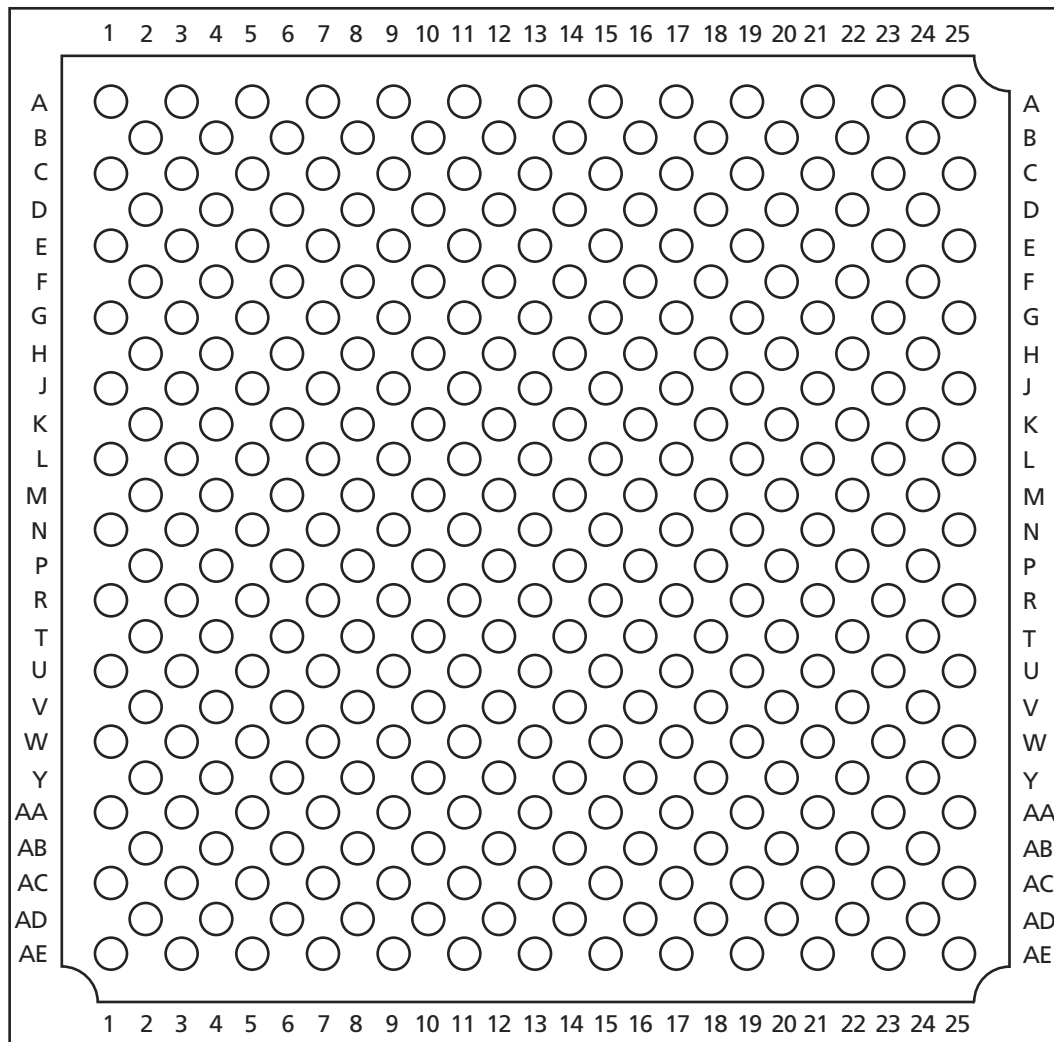


Figure 2-6 • 313-Pin PBGA (Top View)

Note

For Package Manufacturing and Environmental information, visit the Package Resource center at <http://www.actel.com/products/rescenter/package/index.html>.

329-Pin PBGA		329-Pin PBGA		329-Pin PBGA		329-Pin PBGA	
Pin Number	A54SX32 Function	Pin Number	A54SX32 Function	Pin Number	A54SX32 Function	Pin Number	A54SX32 Function
A1	GND	AA13	I/O	AC2	V _{CCI}	B14	I/O
A2	GND	AA14	I/O	AC3	NC	B15	I/O
A3	V _{CCI}	AA15	I/O	AC4	I/O	B16	I/O
A4	NC	AA16	I/O	AC5	I/O	B17	I/O
A5	I/O	AA17	I/O	AC6	I/O	B18	I/O
A6	I/O	AA18	I/O	AC7	I/O	B19	I/O
A7	V _{CCI}	AA19	I/O	AC8	I/O	B20	I/O
A8	NC	AA20	TDO, I/O	AC9	V _{CCI}	B21	I/O
A9	I/O	AA21	V _{CCI}	AC10	I/O	B22	GND
A10	I/O	AA22	I/O	AC11	I/O	B23	V _{CCI}
A11	I/O	AA23	V _{CCI}	AC12	I/O	C1	NC
A12	I/O	AB1	I/O	AC13	I/O	C2	TDI, I/O
A13	CLKB	AB2	GND	AC14	I/O	C3	GND
A14	I/O	AB3	I/O	AC15	NC	C4	I/O
A15	I/O	AB4	I/O	AC16	I/O	C5	I/O
A16	I/O	AB5	I/O	AC17	I/O	C6	I/O
A17	I/O	AB6	I/O	AC18	I/O	C7	I/O
A18	I/O	AB7	I/O	AC19	I/O	C8	I/O
A19	I/O	AB8	I/O	AC20	I/O	C9	I/O
A20	I/O	AB9	I/O	AC21	NC	C10	I/O
A21	NC	AB10	I/O	AC22	V _{CCI}	C11	I/O
A22	V _{CCI}	AB11	PRB, I/O	AC23	GND	C12	I/O
A23	GND	AB12	I/O	B1	V _{CCI}	C13	I/O
AA1	V _{CCI}	AB13	HCLK	B2	GND	C14	I/O
AA2	I/O	AB14	I/O	B3	I/O	C15	I/O
AA3	GND	AB15	I/O	B4	I/O	C16	I/O
AA4	I/O	AB16	I/O	B5	I/O	C17	I/O
AA5	I/O	AB17	I/O	B6	I/O	C18	I/O
AA6	I/O	AB18	I/O	B7	I/O	C19	I/O
AA7	I/O	AB19	I/O	B8	I/O	C20	I/O
AA8	I/O	AB20	I/O	B9	I/O	C21	V _{CCI}
AA9	I/O	AB21	I/O	B10	I/O	C22	GND
AA10	I/O	AB22	GND	B11	I/O	C23	NC
AA11	I/O	AB23	I/O	B12	PRA, I/O	D1	I/O
AA12	I/O	AC1	GND	B13	CLKA	D2	I/O

329-Pin PBGA		329-Pin PBGA		329-Pin PBGA		329-Pin PBGA	
Pin Number	A545X32 Function	Pin Number	A545X32 Function	Pin Number	A545X32 Function	Pin Number	A545X32 Function
D3	I/O	F22	I/O	K20	I/O	N11	GND
D4	TCK, I/O	F23	I/O	K21	I/O	N12	GND
D5	I/O	G1	I/O	K22	I/O	N13	GND
D6	I/O	G2	I/O	K23	I/O	N14	GND
D7	I/O	G3	I/O	L1	I/O	N20	NC
D8	I/O	G4	I/O	L2	I/O	N21	I/O
D9	I/O	G20	I/O	L3	I/O	N22	I/O
D10	I/O	G21	I/O	L4	V _{CCR}	N23	I/O
D11	V _{CCA}	G22	I/O	L10	GND	P1	I/O
D12	V _{CCR}	G23	GND	L11	GND	P2	I/O
D13	I/O	H1	I/O	L12	GND	P3	I/O
D14	I/O	H2	I/O	L13	GND	P4	I/O
D15	I/O	H3	I/O	L14	GND	P10	GND
D16	I/O	H4	I/O	L20	V _{CCR}	P11	GND
D17	I/O	H20	V _{CCA}	L21	I/O	P12	GND
D18	I/O	H21	I/O	L22	I/O	P13	GND
D19	I/O	H22	I/O	L23	NC	P14	GND
D20	I/O	H23	I/O	M1	I/O	P20	I/O
D21	I/O	J1	NC	M2	I/O	P21	I/O
D22	I/O	J2	I/O	M3	I/O	P22	I/O
D23	I/O	J3	I/O	M4	V _{CCA}	P23	I/O
E1	V _{CCI}	J4	I/O	M10	GND	R1	I/O
E2	I/O	J20	I/O	M11	GND	R2	I/O
E3	I/O	J21	I/O	M12	GND	R3	I/O
E4	I/O	J22	I/O	M13	GND	R4	I/O
E20	I/O	J23	I/O	M14	GND	R20	I/O
E21	I/O	K1	I/O	M20	V _{CCA}	R21	I/O
E22	I/O	K2	I/O	M21	I/O	R22	I/O
E23	I/O	K3	I/O	M22	I/O	R23	I/O
F1	I/O	K4	I/O	M23	V _{CCI}	T1	I/O
F2	TMS	K10	GND	N1	I/O	T2	I/O
F3	I/O	K11	GND	N2	I/O	T3	I/O
F4	I/O	K12	GND	N3	I/O	T4	I/O
F20	I/O	K13	GND	N4	I/O	T20	I/O
F21	I/O	K14	GND	N10	GND	T21	I/O

144-Pin FBGA

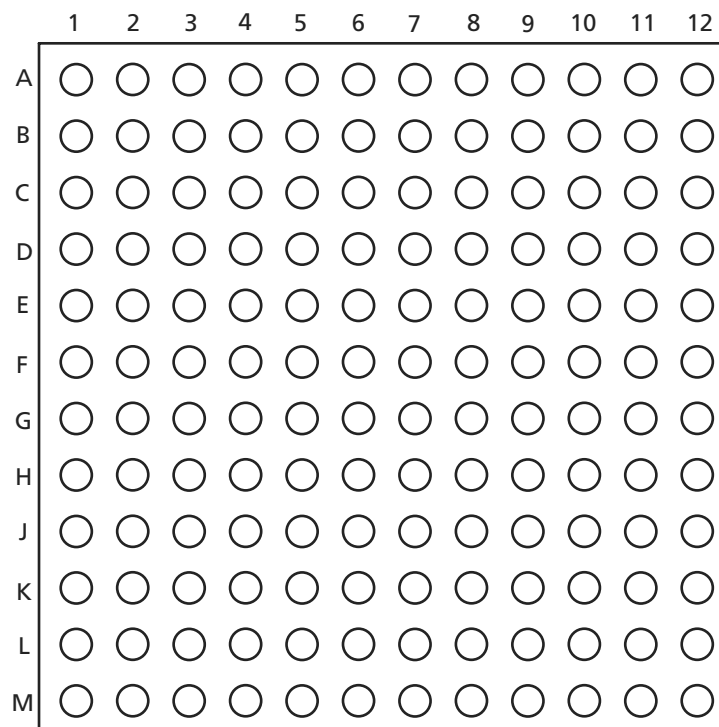


Figure 2-8 • 144-Pin FBGA (Top View)

Note

For Package Manufacturing and Environmental information, visit the Package Resource center at <http://www.actel.com/products/rescenter/package/index.html>.